





VIEW Micro-Metrology Corporate Profile



VIEW Micro-Metrology is a leading supplier of highthroughput optical coordinate measuring machines used in the data storage, electronics, medical, and precision manufacturing industries.

Our family of high speed measurement systems, precision optics, and software provide turnkey metrology solutions for the production line, and general purpose measurement systems for the gage lab.

At VIEW Micro-Metrology, we define productivity as accuracy at speed. Our unique combination of high accuracy and high speed is ideal for electronic assemblies and other parts having hundreds or thousands of critical dimensions that must be monitored. VIEW Micro-Metrology systems can handle features as small as a few microns, or as large as one meter.

VIEW Micro-Metrology operates in a data-driven world. We know it is easier to make promises than it is to deliver results. We minimize our customers' risk by backing up our claims with data. We prove our performance through comprehensive applications studies and performance-based equipment buy-offs.

Our history of innovation and quality dates from 1976 when VIEW Micro-Metrology introduced the world's first 3-axis, automated, vision measurement system. Today, thousands of VIEW Micro-Metrology vision systems are in use in manufacturing applications.

In 2000, VIEW Micro-Metrology joined the Quality Vision International family of companies, a global organization with a 60-year heritage of metrology excellence. Headquartered in Rochester, New York, QVI operates facilities in five US cities and in Frankfurt, Singapore, and Shanghai. QVI companies have installed over 10,000 dimensional measurement systems in 63 countries worldwide.

At VIEW Micro-Metrology, we deliver high productivity and low cost of ownership by combining world-class imaging, video measurement technology with reliable, accurate platforms, and the industry's most capable software. Let us show you the advantages of partnering with VIEW Micro-Metrology.



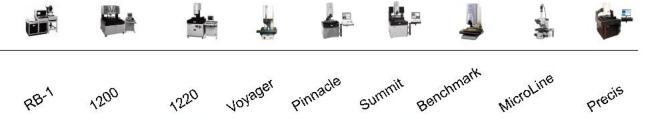








30 YEARS OF INNOVATION IN THE MAKING



1976 2009



The **MicroLine™** is a high-performance critical dimension measurement system for wafers, masks, MEMs, and other micro-fabricated devices. The MicroLine combines full feature microscope measurements at up to 100X with the option of transmitted illumination and an automated stage.



The **VIEW Micro-Metrology Benchmark 250** is a compact, general purpose metrology system with all the features and capabilities of the larger VIEW Micro-Metrology models. With a work envelope of 300 x 150 x 150 mm, the Benchmark 250 can accommodate a wide range of part sizes, and is rugged enough to be located in either a QA lab or an inspection station on the production floor.



The VIEW Micro-Metrology Pinnacle 250 offers the highest accuracy and fastest speed of the VIEW Micro-Metrology line. Its high performance and compact footprint makes it VIEW Micro-Metrology's most popular model. The Pinnacle is ideal for measurement of small, close tolerance parts, such as hard disk drive suspensions, printer heads, leadframes, ball-grid arrays, and chip-scale packages.



The **VIEW Micro-Metrology Summit** family of systems provides high accuracy in a large measurement envelope. Summit is ideal for measurement of large format parts requiring high accuracy, such as solder paste stencils and screens, PCB artwork, panelized circuit boards, flex circuits, and micro-etched parts.



The Precis™ 200 is an optical critical-dimension metrology system for microcomponents, wafers, masks, MEMs, and HDD heads. The Precis combines precision stages, proven microscope optics, and a choice of three world-class metrology software packages to provide new levels of capability for process metrology. The Precis delivers sub-micron field-of-view and point-to-point measurement accuracy on wafers, masks, and micro-fabricated parts.

www.viewmm.com Email: info@viewmm.com